

Search Notes

Application/Control No.

10/521,052

Examiner

David Q. Nguyen

Applicant(s)/Patent under
Reexamination

WIESE ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	418	10/24/06	MD
342	458		
340	506		
301	036		
340	988		
340	416.25	10/24/06	MD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East search	10/24/06	MD